

PERFORMANCE SPECIFICATION

RESISTORS, FIXED, FILM,
NONESTABLISHED RELIABILITY, ESTABLISHED RELIABILITY, AND SPACE LEVEL,
GENERAL SPECIFICATION FOR

This amendment forms a part of MIL-PRF-55182G, dated 9 June 1997, and is approved for use by all Departments and Agencies of the Department of Defense.

PAGE 16 and PAGE 17

TABLE XI, delete and substitute:

"TABLE XI. Qualification inspection.

Inspection	Requirements paragraph	Method paragraph	Number of samples	Number of defects permitted
<u>Certification requirements</u>				
Aqueous-extract-conductivity <u>2/</u>	3.5.1	4.8		<u>1/</u>
Flux <u>2/</u>	3.5.4			
Outgassing (space level only)	3.32	4.8.26		
<u>Group I</u>				
Visual and mechanical examination <u>3/</u>	3.1, 3.4, 3.5, 3.5.1.1 through 3.5.3.2 inclusive, 3.5.5, 3.31, 3.31.1, and 3.32	4.8.1	All sample units	N/A
Thermal shock <u>4/</u>	3.8	4.8.2		
Overload <u>4/</u>	3.9	4.8.3		
DC resistance <u>4/</u>	3.11	4.8.5		
Hermetic seal (when applicable) <u>4/</u>	3.12	4.8.6		
<u>Group IA</u>				
Solderability	3.13	4.8.7	12 sample units	0
Resistance to solvents	3.14	4.8.8		
<u>Group II</u>				
Resistance temperature characteristics	3.15	4.8.9	30	10 highest 10 critical 10 lowest
Low temperature storage	3.29	4.8.23		
Low temperature operation	3.16	4.8.10		
Terminal strength	3.17	4.8.11		
Hermetic seal (when applicable)	3.12	4.8.6		
<u>Group III</u>				
Dielectric withstanding voltage	3.18	4.8.12	30	10 highest 10 critical 10 lowest
Insulation resistance	3.19	4.8.13		
Resistance to soldering heat	3.20	4.8.14		
Moisture resistance	3.21	4.8.15		
<u>Group IV</u>				
Shock (specified pulse)	3.22	4.8.16	30	10 highest 10 critical 10 lowest
Vibration, high frequency	3.23	4.8.17		
Hermetic seal (when applicable)	3.12	4.8.6		

See footnotes at end of table.

MIL-PRF-55182G
AMENDMENT 1

"TABLE XI. Qualification inspection - Continued.

Inspection	Requirements paragraph	Method paragraph	Number of samples	Number of defects permitted
<u>Group V</u> Life	3.24	4.8.18	34 highest 102 34 critical 34 lowest	1
<u>Group VA</u> <u>6/</u> +70°C power rating	3.24.3	4.8.18	34 highest 102 34 critical 34 lowest	1
<u>Group VI</u> High temperature exposure	3.25	4.8.19	<u>7/</u> 102 34 highest 34 critical 34 lowest	1
<u>Group VII</u> Voltage coefficient (applicable to resistors of 1,000 ohms and over) Fungus Mechanical shear (when applicable)	3.26 3.27 3.28	4.8.20 4.8.21 4.8.22	10 highest	0
<u>Group VIII (space level only)</u> Thermal shock (100 cycles)	3.8	4.8.2	10 highest 30 10 critical 10 lowest	0

- 1/ Failure of a resistor in one or more tests of a group shall be charged as a single defect.
2/ The manufacturer shall verify by certification that these requirements have been met in fabricating resistors furnished to this specification.
3/ Marking shall be considered defective if the marking is illegible or incorrect. The two additional unenclosed sample units shall be subjected to the visual and mechanical examination of group I only. Marking shall remain legible at the end of all tests.
4/ As an option, the manufacturer may perform group A, subgroup 1 tests with the required PDA in lieu of these tests.
5/ For characteristic C and characteristic E, zero failures are permitted in moisture resistance.
6/ The power rating shall be +70°C. Qualification inspection only.
7/ Ten sample units shall be subjected to dielectric withstanding voltage and insulation resistance following this test."

Custodians:
Army - CR
Navy - EC
Air Force - 85
NASA - NA

Preparing activity:
Army - CR
Agent:
DLA - CC

Review activities:
Army - AR
Navy - AS, CG, MC, OS
Air Force - 17, 19, 99

(Project 5905-1492)